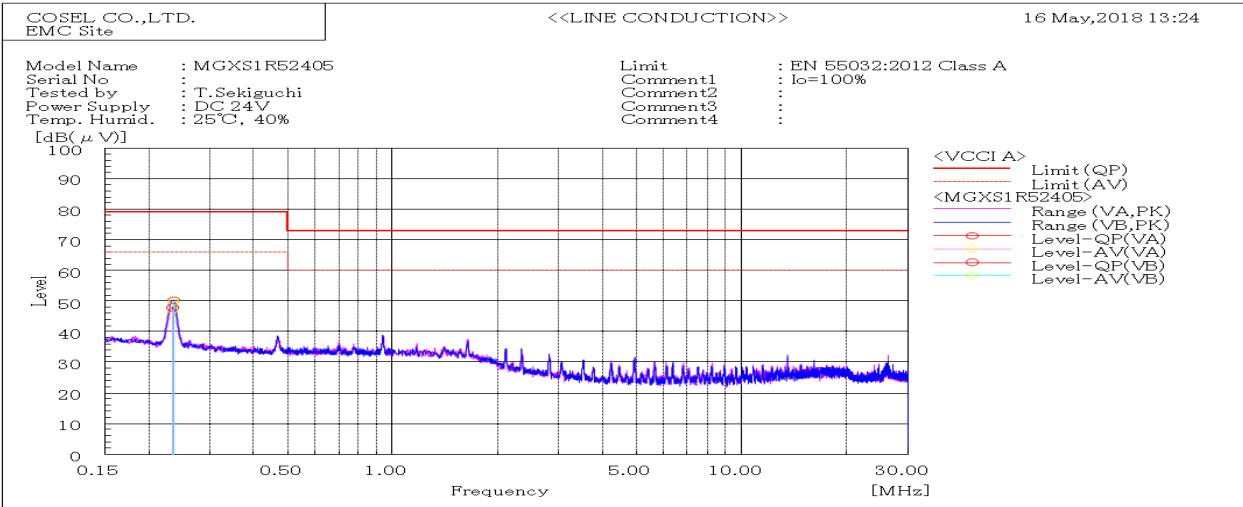
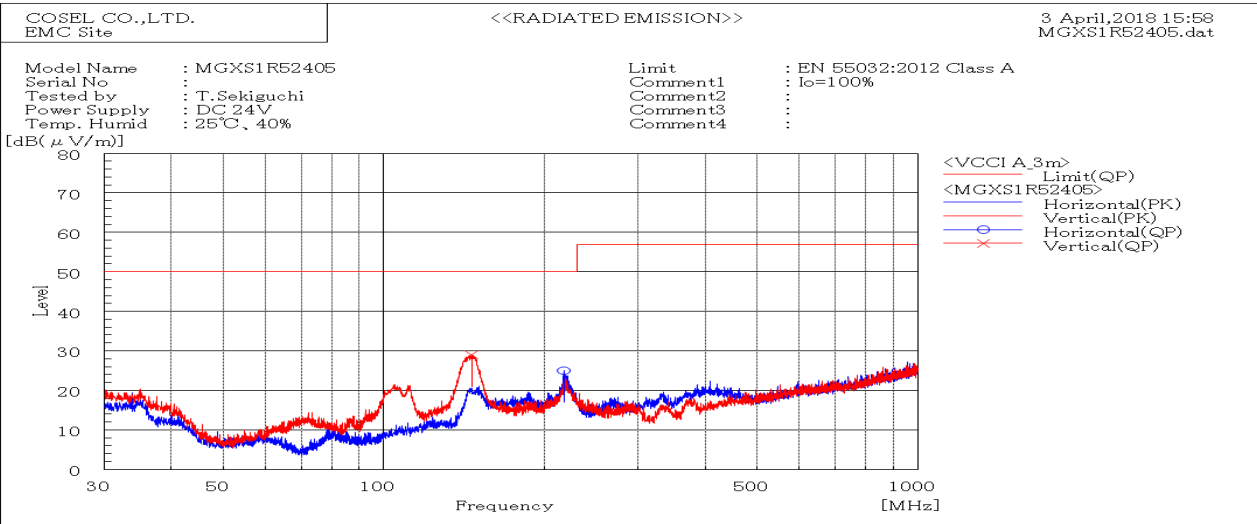


DATA SHEET		Date	18-Apr-18
Model	MGXS1R52405	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sekiguchi



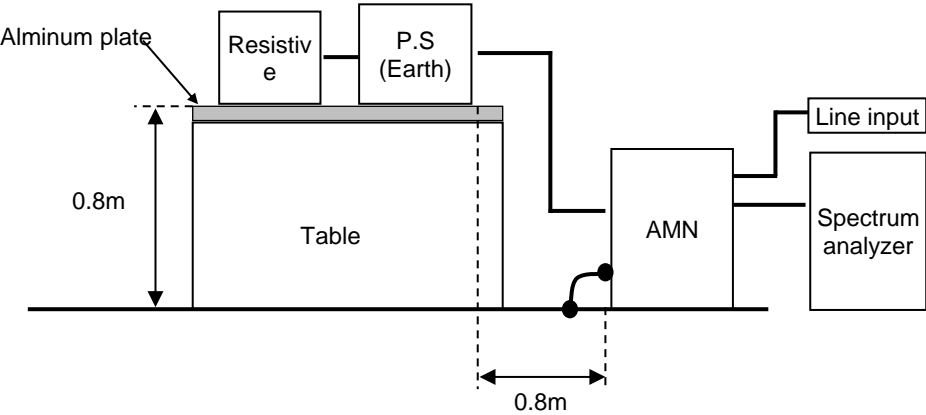
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.2354	VB	50.3	49.8	79	66	28.7	16.2	Pass	
0.23361	VA	47.9	47	79	66	31.1	19	Pass	



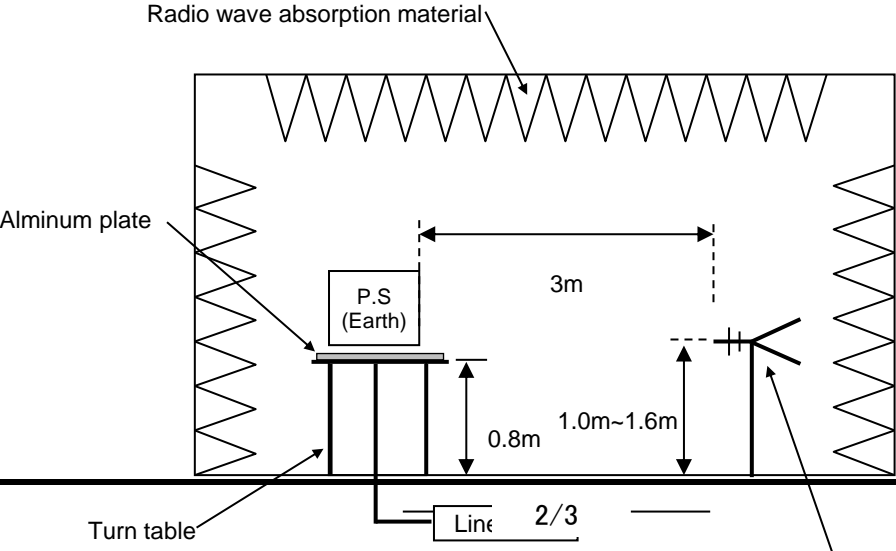
Frequency MHz	Polarization	Stability	Level dB(μV)	Limit dB(μV/m)	Margin dB(μV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
146.987	V	Stable	23.3	50.0	26.7	Pass	104	359	
217.585	H	Stable	20.9	50.0	29.1	Pass	146	250	

DATA SHEET		Date	18-Apr-18
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI	Humid.	40 %RH
	Line conduction & Radiated emission	Tested by	T.Sekiguchi

1. Line conduction



2. Radiated emission

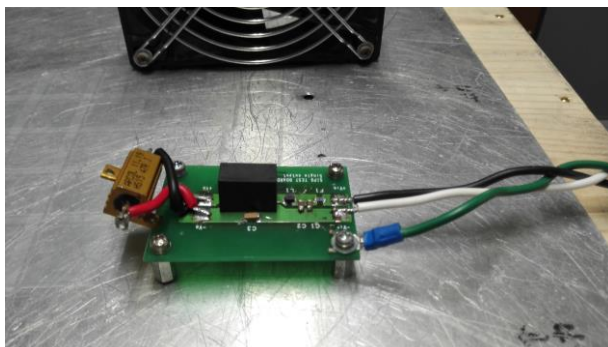


## Conditions

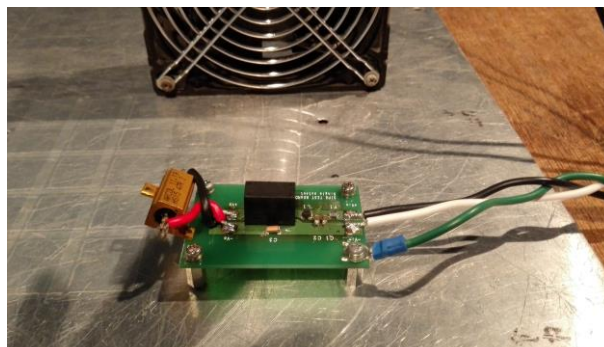
Test : EMI  
Model Name : MGXS1R5□□

○Photographs of Test Set-Up

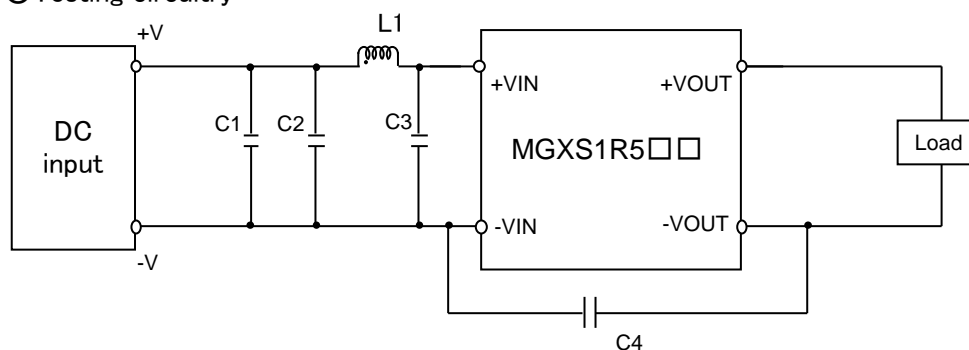
### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry



- C1 : MGXS1R524□□ 100V 2.2  $\mu$  F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING)
- C2 : MGXS1R524□□ 100V 2.2  $\mu$  F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING)
- C3 : MGXS1R524□□ 100V 2.2  $\mu$  F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING)
- C4 : MGXS1R524□□ 2kV 1000pF Ceramic capacitor (GR442QR73D102K MURATA MANUFACTURING)
- L1 : MGXS1R524□□ 310mA 47  $\mu$  H Inductor (LQH32PN470MN0 MURATA MANUFACTURING)